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| Notice of References Cited | Application/Control No. 10/054,509 | Applicant(s)/Patent Under Reexamination BESHAI ET AL. | |
| | Examiner Andrew Lee | Art Unit 2616 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|--------------------|----------------|
| * | A | US-6,560,196 | 05-2003 | Wei, Sherry Xiaobo | 370/230.1 |
| * | B | US-6,317,415 | 11-2001 | Darnell et al. | 370/230 |
| * | C | US-6,118,762 | 09-2000 | Nomura et al. | 370/230 |
| * | D | US-5,953,318 | 09-1999 | Nattkemper et al. | 370/236 |
| * | E | US-5,745,486 | 04-1998 | Beshai et al. | 370/395.71 |
| * | F | US-5,636,212 | 06-1997 | Ikeda, Chinatsu | 370/233 |
| * | G | US-5,634,006 | 05-1997 | Baughner et al. | 709/228 |
| * | H | US-6,405,257 | 06-2002 | Gersht et al. | 709/235 |
| * | I | US-6,091,740 | 07-2000 | Karasawa, Satoru | 370/458 |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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